	Туре	Hits	Search Text	DBs	Time Stamp	Comments
н	BRS	2	<pre>improv\$3 with edge\$1 with signal\$1 with (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1)</pre>	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27	
2	BRS	2	<pre>improv\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1)</pre>	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 09:33	
m	BRS	18	tim\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 09:47	
7	BRS	<del>, - 1</del>	tim\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or digital with processing with system\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:01	

	Type	Hits	S S S S	DBs	Time Stamp	Comments
വ	BRS	m	edge\$1 with me (DUT or lj under adj (integrated adj r IC\$1) and ital with	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:02	
9	BRS	89	with edge\$1 with 1\$1 same (DUT or  =\$1 adj under adj  with (integrated adj  it\$1 or IC\$1) and  or (data or digit\$2)  process\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:02	
	BRS	0	\$1 with DUT or der adj egrated adj \$1) and r digit\$2) and comput\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:03	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
. ω	BRS	ഗ	edge\$1 with ame (DUT or dj under adj (integrated adj) or IC\$1) and ata or digit\$2) ss\$3) and 3 or comput\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:29	
. 6	BRS		dj [	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:30	
10	BRS	m	tim\$3 with edge\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and calculat\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:31	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
11	BRS	4	edge\$1 same vice\$1 adj under with (integrated t\$1 or IC\$1) and ata or digit\$2) ss\$3) and	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:31	
12	BRS	7	tim\$3 with edge\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and accurac\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:32	
13	BRS.	21	tim\$3 with edge\$1 same accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:45	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
14	BRS	13	edge\$1 with  nd (DUT or  lj under adj  (integrated adj  or IC\$1) and  ita or digit\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:51	·
15	BRS	. 6	1 with UT or er adj grated adj 1) and digit\$2) and nal\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:52	
16	BRS	10	<u> </u>	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:52	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
17	BRS	<b>-</b> 7	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 with accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:53	
18	BRS	12	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 and accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:02	

	Type	Hits	Search Text	DBs	Time Stamp Comments	Comments
о О	BRS	4	ınd dj	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:02	
20	BRS	5.	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 and accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and error\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:03	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
21	BRS	12	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 and accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:03	
22	BRS	15	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:04	

	Type	Hits	Search Text	DBs	Time Stamp Comments	Comments
23	BRS	O	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:05	
24	BRS	7	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 same (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1 and (DUT or device\$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:07	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
,			(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1			
			same (integrated adj circuit\$1 or IC\$1) and			·
			· 7			
			with process\$3) and	US-PGPUB;		4
25	BRS	7	with tim\$3 and	USPAT; EPO;	2006/03/27	
			and (DUT or	JPO; DERWENT;	11:07	
			\$1 adj under adj	IBM_TDB		
			reference\$1			
			threshold\$1 or desired or			
			term			
			with tim\$3			
			3 or a			
			with			
	•		(integrated adj circuit\$1			
			or IC\$1) and (DPS or (data			
			) with	י פוזפיים - סוז		
			and cycle\$1		60/00/000	
56	BRS	4	and clock\$1 and	USEAL; EFU;	2006/03/2/	
			(DUT or device\$1 adj under	OFO, DEKWENT,	80:11	
			·			
			or threshold\$1 or desired			
			or expected or predefined			
			or predetermined or			
		7	preset\$4) with tim\$3		-	

Comments	
Time Stamp Comments	2006/03/27 11:08
DBs	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
Search Text	(calibrat\$3 or adjust\$3) with tim\$3 with edg\$3 and test\$3 with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1 and (DUT or device\$1 adj under adj test) and (reference\$1 or threshold\$1 or desired or expected or predefined or predetermined or preset\$4) with tim\$3
Hits	
Type	BRS
	27

	Туре	Hits	Search Text	DBs	Time Stamp	Comments
	BRS	20	(calibrat\$3 or adjust\$3) with tim\$3 with edg\$3 and test\$3 with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1 and (DUT or device\$1 adj under adj test) and (reference\$1 or threshold\$1 or desired or expected or predefined or predetermined or preset\$4) with tim\$3 and computer\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27	
29	BRS	9747	702/57,69.ccls. or 714/724,742,744.ccls. or 324/158.1.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2006/03/27 11:10	
30	BRS ,	2	<pre>improv\$3 with edge\$1 with signal\$1 with (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1)</pre>	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 09:33	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
31	BRS	2	<pre>improv\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1)</pre>	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 09:33	
32	BRS	19.	th edge\$1 with same (DUT or adj under adj th (integrated adj 1 or IC\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 09:49	
	BRS		(expected or desired) with tim\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 09:49	•
34	BRS	2.	"20060036387"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2006/03/27 09:58	
	BRS		tim\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or digital with processing with system\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:01	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
98	BRS	<b>m</b> .	tim\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or digital with process\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:02	
37	BRS		tim\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:02	
38	BRS	. 0	tim\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and (calculat\$3 or comput\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:11	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
·			(compar\$4 or differen\$2) with tim\$3 with edge\$1			
			with signal\$1 with			
	•		(threshold\$1 or			
			reference\$1 or expected or			
			desired or predetermined	US-PGPUB;		
39	BRS	0	preset\$4 or predefined)	USPAT; EPO;	2006/03/27.	
) )	?		or device\$1 adj	JPO; DERWENT;	10:15	
			j test) with	IBM TDB		
			(integrated adj circuit\$1	I		
	•					
			or digit\$2) with			,
			process\$3) and (calculat\$3			
			or comput\$3) with error\$1			
r -	,		ינו			
			signal\$1 with (threshold\$1			
			or reference\$1 or expected			
			or desired or	US-PGPUB;		
0	pod		predetermined or preset\$4 (	USPAT; EPO;	2006/03/27	
) !'	2	<b>-</b>	ned) same (DUT	JPO; DERWENT;	10:17	
			r device\$1 adj under adj	IBM TDB		
			t) with	l	,	
			or digit\$2) with			
			process\$3)			

· .	Type	Hits	Search Text	DBs	Time Stamp	Comments
4.1	BRS	5.6	tim\$3 with edge\$1 with signal\$1 with (threshold\$1 or reference\$1 or expected or desired or preset\$4 or predetermined or preset\$4 or predefined) same (DUT or device\$1 adj under adj test) and (DPS or (data or digit\$2) with process\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:20	
42	BRS	. ret	tim\$3 with occurrence\$1 with edge\$1 with signal\$1 with (DUT or device\$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2006/03/27	
43	BRS		(threshold\$1 or reference\$1 or expected or desired or predetermined or preset\$4 or predefined) with tim\$3 with point\$1 with edge\$1 with signal\$1 same (DUT or device\$1 adj	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:26	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
44	BRS	3 o	(threshold\$1 or reference\$1 or expected or desired or predetermined or preset\$4 or predefined) with tim\$3 with point\$1 with edge\$1 with signal\$1 and (DUT or device\$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:27	
45	BRS		(determin\$3 or calculat\$3 or computing or comput or computa) with (threshold\$1 or reference\$1 or expected or desired or predetermined or preset\$4 or predefined) with tim\$3 with point\$1 with edge\$1 with signal\$1 and (DUT or device\$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:27	
46	BRS	<u>.</u>	3 with edge\$1 with al\$1 same (DUT or ce\$1 adj under adj with (integrated adj uit\$1 or IC\$1) and or (data or digit\$2) process\$3) and culat\$3 or comput\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:29	

·	Type	Hits	Search Text	DBs	Time Stamp	Comments	•
47	BRS	M	tim\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj Circuit\$1 or IC\$1) and (DPS or (data or digit\$2) I with process\$3) and calculat\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:30		•
4.8	BRS	ю	edge\$1 same vice\$1 adj under with (integrated t\$1 or IC\$1) and ata or digit\$2) ss\$3) and	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:31		
49	BRS	4	tim\$3 with edge\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and error\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:31		

	Type	Hits	Search Text	DBs	Time Stamp	Comments
50	BRS	7	tim\$3 with edge\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and accurac\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:32	
51	BRS	23	edge\$1 same and (DUT or dj under adj (integrated adj or IC\$1) and ata or digit\$2) ss\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:46	
52	BRS .	40	tim\$3 with edge\$1 same occur\$6 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:49	,

	Type	Hits	Search Text	DBs	Time Stamp	Comments
53	BRS	24	dj )	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:50	
54	BRS	0	with tim\$3 with th occur\$6 and evice\$1 adj under with (integrated it\$1 or IC\$1) and data or digit\$2) ess\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:50	
55	BRS	4	compar\$4 same tim\$3 with edge\$1 with occur\$6 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:50	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
56	BRS	14	with T or r adj rated adj ) and digit\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:51	
57	BRS	10	edge\$1 with and (DUT or dj under adj (integrated adj or IC\$1) and ata or digit\$2) ss\$3) and th signal\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:52	
28	BRS	11	ch dj ed adj nd it\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:52	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
			(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 with accurac\$3 and (DUT or			
59	BRS	. 2	dj under adj (integrated adj or ICS1) and	US-PGPUB; USPAT; EPO; JPO; DERWENT;	2006/03/27 10:58	
			data or digit\$2)	IBM_TDB	*	
	•		cycle\$1 with tim\$3			
			(calibrat\$3 or adjust\$3 or compensat\$3) with tim\$3			
			C\$3.	JS-PGPUB;		
09	BRS	<u></u>	test) with adj circuits1	USPAT; EPO; JPO; DERWENT;	2006/03/27 10:59	
			20.00			
. •			process\$3) and cycle\$1			
			with tim\$3			

	Type	Hits	Search Text	DBs	Time Stamp	Comments
61	BRS	. H	nd dj	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:02	
62	BRS	5	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 and accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and instruct\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:03	

	Туре	Hits	Search Text	DBs	Time Stamp	Comments
63	BRS	13	(calibrat\$3 or adjust\$3 or compensat\$3) with tim\$3 with tim\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data) or digit\$2) with process\$3) and cycle\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:02	
64	BRS	D.	\$3 or adjust\$3 or \$3) with tim\$3 \$1 and accurac\$3 or device\$1 adj test) with ed adj circuit\$1 and (DPS or (data 2) with ) and cycle\$1 3 and instruct\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:03	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
65	BRS	. 9	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 and accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and error\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:03	
99	BRS	6	(calibrat\$3 or adjust\$3 or compensat\$3) with tim\$3 with tim\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and error\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:03	

	Type	Hits	Search Text	DBs	Time Stamp Comments	Comments
67	BRS	۳ ا	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 and accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:03	
89	BRS	13	calibrat\$3 or adjust\$3 or ompensat\$3) with tim\$3 ith edge\$1 and accurac\$3 nd (DUT or device\$1 adjuntegrated adj circuit\$1 r IC\$1) and (DPS or (datar digit\$2) with rocess\$3) and cycle\$1 ith tim\$3 and clock\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27	

	Type	Hits	Search Text	DBs	Time Stamp	Comments
6 9	BRS	17	or adj	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:04	
02	BRS	0	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:07	

	Туре	Hits	Search Text	DBs	Time Stamp	Comments
			(calibrat\$3 or adjust\$3 or compensat\$3) with tim\$3 with edge\$1 same			
7	BRS	. rv .	ed adj circuit\$1 and (DPS or (data 2) with	US-PGPUB; USPAT; EPO; JPO; DERWENT;	2006/03/27	
			nd cycle\$1 nd clock\$1 and	IBM_TDB		
	٠.		(DUT or device\$1 adj under adj test)			
			(calibrat\$3 or adjust\$3 or compensat\$3) with tim\$3			
			with edge\$1 same (integrated adj circuit\$1 or IC\$1) and (DPS or (data			
72	BRS	r)	and cycle\$1 and clock\$1 and	PGPUB; AT; EPO; ; DERWENT;	2006/03/27 11:07	
			evices! adj under and (references! olds! or desired	IBM_TDB		
			or expected or predefined or predetermined or preset\$4) with tim\$3			

	Type	Hits	Search Text	DBs	Time Stamp Comments	Comments
			(calibrat\$3 or adjust\$3 or compensat\$3) with tim\$3		·	
			with edg\$3 same (integrated adj circuit\$1			
			or IC\$1) and (DPS or (data			
			or digit\$2) with	US-PGPUB;		
73	סממ	Ľ	process\$3) and cycle\$1	USPAT; EPO;	2006/03/27	
? .	o Vi	)	with tim\$3 and clock\$1 and JPO; DERWENT;	JPO; DERWENT;	11:08	
	•		(DUT or device\$1 adj under IBM_TDB	IBM_TDB		
			adj test) and (reference\$1			
		ú	or threshold\$1 or desired			
			or expected or predefined			
			or predetermined or	-		
			preset\$4) with tim\$3			

	Type	Hits	Search Text	DBs	Time Stamp	Comments
			(calibrat\$3 or adjust\$3 or			
			compensat\$3) with tim\$3			
			with edg\$3 and test\$3 with	•		
			(integrated adj circuit\$1	•		
•			or IC\$1) and (DPS or (data			
			or digit\$2) with c	US-PGPUB;		
74	S S S S	30	process\$3) and cycle\$1	USPAT; EPO;	2006/03/27	
		1	with tim\$3 and clock\$1 and JPO; DERWENT;	JPO; DERWENT;	11:09	
			(DUT or device\$1 adj under IBM TDB	IBM TDB		
			adj test) and (reference\$1			
			or threshold\$1 or desired			
			or expected or predefined			
•	•		or predetermined or	٠.		
			preset\$4) with tim\$3			

	Type	Hits	Search Text	DBs	Time Stamp	Comments
			(calibrat\$3 or adjust\$3 or compensat\$3) with tim\$3 with edgs 3 and test\$3 with			
			egrated adj circui			
7.5	დ დ დ	24		US-PGPUB; USPAT; EPO;	2006/03/27	·
			or device\$1 adj under est) and (reference\$1	JPO; DERWENT; IBM_TDB	11:09	
			thresho			
			or expected or predelined or predetermined or			
			preset\$4) with tim\$3 and			
		*	ccls. or		. •	
	•		/24,/42,/44.ccls. or 158.1.ccls.) and tim\$3	US-PGPUB;	76/80/9006	
9/	BRS	∞ <del>⊢</del>	<pre>with point\$1 with edge\$1 with signal\$1 and (DUT or )</pre>	JPO; DERWENT;	11:18	٠.
	<u>.</u> .		() ~	1 BM _ 1 DB		
			rest)			

	Type	Hits	Search Text	DBs	Time Stamp	Comments
77	BRS	Q	59.ccls. or 742,744.ccls. or 1.ccls.) and tim\$3 or 1.t\$1 with edge\$1 or 1.cl\$1 same (DUT or adj under adj	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:13	-
78	BRS	2	(702/57,69.ccls. or 714/724,742,744.ccls. or 324/158.1.ccls.) and tim\$3 with point\$1 with edge\$1 with signal\$1 with (DUT or device\$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:13	
79	BRS	112	th point\$1 with th signal\$1 and levice\$1 adj under	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2006/03/27 11:17	
80	BRS	23	(702/57,69,117.ccls. or 714/724,742,744.ccls. or 324/158.1.ccls.) and tim\$3 with point\$1 with edge\$1 with signal\$1 and (DUT or device\$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:24	

	Туре	Hits	Search Text	DBs	Time Stamp	Comments
81	BRS	98	("702"/\$.ccls. or "714"/\$.ccls. or "324"/\$.ccls.) and tim\$3 with point\$1 with edge\$1 with signal\$1 and (DUT or device\$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:19	
82	BRS	42	(702/57,69,117,119.ccls.) or 714/700,718,724,736,742,74 3,744,815.ccls. or 324/158.1.ccls.) and tim\$3 with point\$1 with edge\$1 with signal\$1 and (DUT or device\$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:25	
88	BRS	2.43	r r 14/700,718,724,736,742,74 ,744,815.ccls. or 24/158.1.ccls.) and tim\$3 ith edge\$1 with signal\$1 nd (DUT or device\$1 adj nder adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:31	

Hits	rn	Search Text	DBs	Time Stamp	Comments
) C	1 - C	(702/57,69,117,119.ccls.			·
7	7	736,742,74	US-PGPUB;		
116 3	m	occls. or	USPAT; EPO;	2006/03/27	
Ϋ́ ¾	n 3	and times	JPO; DEKWENT; TRM TOR	11:25	
	<u> </u>	(DUT or device\$1 ad		·	
_ =	_=	r adj test)			
)	<u> </u>	(702/57, 69, 117, 119.ccls.			•
0	0	, H			
7	7	.8,724,736,742,74	US-PGPUB;	•	
33	$\mathfrak{C}$		USPAT; EPO;	2006/03/27	
	m	ccls.) and tim\$3	JPO; DERWENT;	11:27	
M	<u>`</u>	edge\$1 with signal\$1	IBM_TDB		
W	3	(DUT or devi			
Ų	$\Box$	λj	•		·
<u>)</u>		(702/57, 69, 117, 119.ccls.		·	*
	O	Я			
7	_	714/700,718,724,736,742,74			
3	$\mathfrak{C}$		מזים של מזים	2006/03/27	
	$\infty$	ccls.) and tim\$3		11:29	
<u>M</u>	_≥	\$1 with			
<u> </u>	_≥	r dev			
<u> </u>	$\Box$	under adj test)		-	

	Туре	Hits	Search Text	DBs	Time Stamp	Comments
87	BRS	12	(count\$3 or occur\$6 or number\$1) with tim\$3 with edge\$1 with signal\$1 with (DUT or device\$1 adj under adj test)	US-PGPUB	2006/03/27 12:28	
88	BRS	4	or differen\$2) nt\$3 or occur\$6 \$1) with tim\$3 \$1 with signal\$1 or device\$1 adj test)	US-PGPUB	2006/03/27 11:30	
<u>ა</u>	BRS		117,119.ccls.  724,736,742,74 cls. or cls.) and tim\$3 with signal\$1 device\$1 adj est)	US-PGPUB	2006/03/27 11:31	
06	BRS	170	gnal\$1 with cycle\$1 with	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2006/03/27 11:46	
91	BRS	7.0	generat\$3 with cycle\$ with signal\$1 with tester\$1 with cycle\$1 with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2006/03/27 11:47	

							_
	Type	Hits	Search Text	DBs	Time Stamp	Comments	
6	BRS	9	generat\$3 with cycle\$ with edge with signal\$1 with tester\$1 with cycle\$1 with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2006/03/27		
6	BRS	7	generat\$3 with cycle\$ with edge with signal\$1 with (DUT or device adj under adj test\$3) or tester\$1) with cycle\$1 with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:50		,
	BRS	12	(count\$3 or occur\$6 or number\$1) with tim\$3 with (peak\$1 or edge\$1) with signal\$1 with (DUT or device\$1 adj under adj test)	US-PGPUB	2006/03/27 12:28	(.	
95	BRS		compar44 with expected with tim\$3 with edge with signal\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2006/03/27 12:55		
96	BRS	40	compar\$4 with expected with tim\$3 with edge with signal\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2006/03/27 12:55		· · · · · · · · · · · · · · · · · · ·

	Type	Hits	Search Text	DBs	Time Stamp	Comments
97	BRS		compar\$4 with expected with tim\$3 with edge with signal\$1 same (DUT or device\$1 adj under adj test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 12:56	
86	BRS	2	compar\$4 with (desired or expected) with tim\$3 with edge with signal\$1 same (DUT or device\$1 adj under adj test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 12:56	-
66	BRS	2	(differen\$2 or compar\$4) with (desired or expected) with tim\$3 with edge with signal\$1 same (DUT or device\$1 adj under adj test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 12:56	
100	BRS	10	(differen\$2 or compar\$4) with (desired or expected) with tim\$3 with edge\$1 with signal\$1 and (DUT or device\$1 adj under adj test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_IDB	2006/03/27 13:08	
101	BRS		tim\$3 with edge\$1 with signal\$1 with (DUT or device\$1 adj under adj test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2006/03/27 13:08	

	-Type	Hits	Search Text	DBs	Time Stamp	Comments
102	BRS	14	(adjust\$3 or calibrat\$3 or compensat\$3) with tim\$3 with edge\$1 with signal\$1 with (DUT or device\$1 adjunder adj test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 13:14	
103	BRS	0	t\$3 or m\$3 nal\$1 T or dj	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 13:15	
104	BRS	0	(adjust\$3 or calibrat\$3 or compensat\$3) with (tim\$3 adj edge\$1) with signal\$1 with ((expected or desired) adj tim\$3) same (DUT or device\$1 adj under adj test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 13:16	·
105	BRS	0		US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 13:16	

adjust\$3 or calibrat\$3 or calibrat\$3 or calibrat\$3 or calibrat\$3 or desired uspensed uspected or desired uspensed uspected or desired uspensed uspected or desired uspensed uspected or desired uspected							
(adjust\$3 or calibrat\$3 or compensat\$3) with (tim\$3 us-pGpUB; adj edge\$1) with signal\$1 USPAT; EPO; with (expected or desired) JPO; DERWENT; and (DUT or device\$1 adj IBM_TDB under adj test\$3) with (tim\$3 adj edge\$1) with signal\$1 with (expected or desired USPAT; EPO; predetermined or preset\$4 JPO; DERWENT; or reference\$1 or threshold\$1) and (DUT or device\$1 adj under adj test\$3) (adjust\$3 or calibrat\$3 or compensat\$3) with (tim\$3 adj edge\$1) with signal\$1 and (DUT or device\$1 adj under adj test\$3) (adjust\$3 or calibrat\$3 or compensat\$3) with (tim\$3 adj edge\$1) with signal\$1 and (expected or desired uspected or desired or predetermined or preset\$4 JPO; DERWENT; or reference\$1 or predetermined or preset\$4 JPO; DERWENT; or reference\$1 or threshold\$1) with tim\$3 with edge\$1 and (UUT or device\$1 adj under adj test\$3)	·	Type		Search Text	DBs	Time Stamp	Comments
(adjust\$3 or calibrat\$3 or compensat\$3) with (tim\$3 adj edge\$1) with signal\$1 with (expected or desired US-PGPUB; or predetermined or preset\$4 JPO; DERWENT; or reference\$1 or threshold\$1) and (DUT or device\$1 adj under adj test\$3) (adjust\$3 or calibrat\$3 or compensat\$3) with (tim\$3 adj edge\$1) with signal\$1 and (expected or desired or predetermined or preset\$4 JPO; DERWENT; or reference\$1 or libm_TDB threshold\$1) with tim\$3 ibm_TDB threshold\$1 with tim\$3 with edge\$1 and (DUT or device\$1 adj under adj thest\$3)	106	BRS		ust\$3 or calibrat\$3 unsat\$3) with (tim\$3 edge\$1) with signal\$ (expected or desire DUT or device\$1 adj	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 13:17	
(adjust\$3 or calibrat\$3 or compensat\$3) with (tim\$3 adj edge\$1) with signal\$1 and (expected or desired or predefined or preset\$4 or predetermined or preset\$4 or caference\$1 or threshold\$1) with tim\$3 threshold\$1 and (DUT or device\$1 adj under adj	107	BRS	9	t\$3 or calibrat\$3 sat\$3) with (tim\$3 ge\$1) with signal\$ expected or desire defined or ermined or preset\$ erence\$1 or old\$1) and (DUT or \$1 adj under adj )	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 13:21	
		BRS		with (tim\$3 with signal\$ d or desired d or preset\$ d or preset\$ d or preset\$ d or preset\$ and (DUT or under adj	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27	-

	Type	Hits	Search Text	DBs	Time Stamp	Comments
109	BRS	Ø	or calibrat\$3 or \$3) with (tim\$3 1) with signal\$1 cted or desired ined or preset\$4 nce\$1 or \$1) with tim\$3 \$1 and cycle\$1 3 and (DUT or adj under adj	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 14:31	
110	BRS	m	(adjust\$3 or calibrat\$3 or compensat\$3) with (tim\$3 adj edge\$1) with signal\$1 and (tester\$1 or DUT or (device\$1 adj under adj test\$3)) with cycle\$1 with time\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 14:33	

Title  OR  RRef  Ind apparatus  tely g test  Ind apparatus  uring timing paths ng a scan sequential elements Ind apparatus brating eskewing ations  Int and ent method ler for an ed circuit Ind apparatus Ind Alala Ind										
US  2006004982 20060309 17 for remotely channels  2006003172 20060209 15 buffering test channels  X 2006003172 20060209 15 by setting a scan mode of sequential storage elements  We Al storage elements  X 2006001035 20060112 21 and/or deskewing for calibrating for and/or deskewing for calibrating for and for any for calibrating for any for calibrating for any for calibrating for and for calibrating for any for calibrating for calibrating for calibrati		Þ	Ħ	Document ID		Page s		Current OR	Current XRef	Retrieva 1
Nethod and apparatus   For measuring				US 2006004982 0 A1	20060309	17	aratus	324/158.1		324/158.
Wethod and apparatus   For calibrating   114/700	N	×		US 2006003172 8 A1	20060209	15	nd apparatus uring timing paths ng a scan sequential elements	714/724		714/724
US	m	×		US 2006001035 8 Al	20060112	21	Method and apparatus for calibrating and/or deskewing communications channels	_	455/67.16	714/700
X       2005024660 20051103 12 integrated circuit       714/742         3 A1       Method and apparatus         US       to measure and display data       714/724         X       2005024660 20051103 display data       714/724 dependent eye dependent eye diagrams	4	×		US 2005026769 6 A1	20051201			702/57		702/57
US  X 2005024660 20051103 display data 1 Al dependent eye diagrams	Ŋ	×		US 2005024660 3 A1		12	coupler for an grated circuit er	714/742		714/742
	v ·	×		US 2005024660 1 A1	20051103		Method and apparatus to measure and display data dependent eye diagrams	714/724		714/724

	n	1 Document	t Issue Date	Page s	Title	Current OR	Current XRef	Retrieva 1 Classif
7	×	US 2005022531 4 A1	31 20051013		Method of measuring duty cycle	324/158.1		324/158.
88	×	us 2005019335 5 Al	20050901	19	Source synchronous timing extraction, cyclization and sampling	716/6	703/19; 714/724	714/724
თ	×	US 200501603 1 A1	US 2005016033 20050721 1 A1		tem timing ent and ion	714/700		714/700
10	×	US 2005009742 0 A1	20050505	26	Apparatus for jitter testing an IC	714/742		714/742
11	×	US 200500881 7 A1	US 2005008816 20050428 7 Al		Isolation buffers with controlled equal time delays	324/158.1		324/158.
12	×	US 2005008058 0 A1	20050414	27	Device for testing lsi to be measured, jitter analyzer, and phase difference detector	702/117		702/117
13	×	US 200500504 1 A1	US 2005005041 20050303 1 A1		Pre-stored digital word generator	714/724		714/724

	D	1 Document ID	t Issue Date	Page s	Title	Current OR	Current XRef	Retrieva 1 Classif
14	×	US . 2005003861 5 Al	51 20050217		Qualification signal measurement, trigger, and/or display system	702/69		702/69
15	×	US 2005003404 4 Al	04 20050210 25		Semiconductor test device and timing measurement method	714/742		714/742
16	×	US 2005002806 2 A1	06 20050203		Test method and apparatus for high-speed semiconductor memory devices	714/736		714/736
17	× .	US 2005002208 8 A1	08 20050127		Semiconductor tester 714/744	714/744		714/744
18	. ×	US 2005002208 1 A1	20050127	42	Test systems and methods with compensation techniques.	714/724		714/724
19	×	US 2005002208 0 Al	20050127	43	d methods with test	714/724		714/724
20	$\times$	US 2004026049 2 A1	20041223	<u>ත</u>	Direct jitter analysis of binary sampled data	702/69		702/69

		-							
	D		Document		Page	Title	Current	Current	Retrieva 1
				Date	ശ		O.Y.	XKet	Classif
21	×	. US	US 2004015326 20040805	20040805		System and method of	69/602		702/69
		7	A1				) )		0
		SN				System and method of			
. 22	×	<u>.</u>	2004012260 20040624	20040624			702/69		702/69
		7	A1			propagation delay			
						(U)			
				* , ,		arbitrary dynamic			
			.•			mappings to	٠,		
		Sn		·		serialize vectors	·		
23	×	. 50	007874	20040422		into transmitted	714/718		714/718
		0	Al			sub-vectors and de-		•	
						serialize received	·		
						sub-vectors into			
						vectors		,	•
						Deskewed	•		·
		SO	ro.			differential			711/700.
24	×		006476	20040401		detector employing	714/700	714/724	714/100/
		·	A1			analog-to-digital			F7//FT/
						converter			
L	, , , , , , , , , , , , , , , , , , ,	SD	(C) (C)	()			() () ()		324/158.
7.25	×	<u> </u>	2004005151 8 Al	Z0040318		with narrow output pulses	324/158.1		
		110				Instrument initiated	-		
26	×	3 6	04000332	20040101		communication for	714/724		714/724
)	·	ία	A1	H H D		automatic test	7 3 / 7 + -		F 3
		)				equipment			

	-	-							
	Þ	+	Document ID	Issue Date	Page s	Title	Current OR	Current XRef	Retrieva 1 Classif
27	×		US 2003023360 4 A1	20031218		Memory device test system and method	714/718		714/718
28	×		03022946 A1	20031211		Test method and apparatus for source synchronous signals	702/117	·	702/117
29	×		US 2003015868 7 A1	20030821	11	Composite eye diagrams	702/117		702/117
30	×			20030703	13	Time shift circuit for functional and AC parametric test	714/724		714/724
31 	_×_		US 2003011712 9 A1	20030626	7	Low-cost tester interface module	324/158.1	324/765	324/158.
32	×		US 2003011042 7 A1	20030612		Semiconductor test system storing pin calibration data in non-volatile memory	714/724		714/724
33	× .	$\times$	US 2003002883 2 A1	20030206	18	uit	714/700		714/700
34	×		US 2003000537 5 Al	20030102		Algorithmically programmable memory tester with test sites operating in a	714/724		714/724

	$\lceil$			1					
	D	· H	Document ID	Issue Date	Page s	Title	Current OR	Current XRef	Retrieva 1 Classif
35	×		US 2002018600 4 Al	20021212		Method for manufacturing smart card and identification devices and the like	324/158.1		324/158.
36	× .		us 2002018458 1 Al	20021205		1/11/2011	714/724		714/724
37	×		US 2002017000 6 A1	20021114	17	Differential receiver architecture	714/724		714/724
38	×		US 2002015243 7 Al	20021017	<u>о</u>	Circuitry for and system and substrate with circuitry for aligning output signals in massively parallel testers and other electronic devices	714/724		714/724
36	×	×	US 2002013535 7 A1	20020926	4 4 4 4	Method and apparatus for socket calibration of integrated circuit testers	324/158.1		324/158.

						•			
	Þ	<del>ri</del> l	Document ID	Issue	Page s	Title	Current OR	Current XRef	Retrieva 1 Classif
40	×		US 2002012587 8 A1	20020912	T + 01 0	High-frequency tester for semiconductor devices	324/158.1		324/158.
41	×		us 2002007776 20020620 3 A1	20020620	7 7 7	Automatic tester having separate coarse and precise timing modules	702/120	702/117	702/117
42	×		US 2002004289 8 Al	20020411	L. P 03 03 A	Test interface for verification of high speed embedded synchronous dynamic random access memory (SDRAM) circuitry	714/744	365/192	714/744
43	×		US 2001001046 20010802 2 A1	20010802		Carrier identification system, carrier identification method and storage media	324/158.1		324/158.